

13th Seminar "Computer Modeling in Microwave Engineering and Applications"

Advances in Determining Material Parameters

March 7-8, 2011

Swiss Federal Laboratories for Materials Science and Technology (EMPA)
Thun, Switzerland

Preliminary Program

Sunday, March 6, 2011

17:00-19:00 **On-site registration: Hotel Krone, Rathausplatz, Thun**

Monday, March 7, 2010

7:15-7:30 **On-site registration:** Hotel Krone, Rathausplatz, Thun

7:15-14:00 **Excursion to the Swiss Light Source (SLS) of the Paul Scherrer
Institute in Villigen, Switzerland**

14:00-14:30 **On-site registration:** EMPA, Room 503

14:30-14:45 **Welcome & Opening remarks**
S. Vaucher, Seminar Vice-Chair & Local Organizer
EMPA, Thun, Switzerland

Introduction to the Seminar
V.V. Yakovlev, Seminar Founder and Chair
Worcester Polytechnic Institute, MA, USA

- 14:50-15:30 **An Overview of Dielectric Properties Measuring Techniques and Instruments**
J. M. Catalá-Civera and F.L. Peñaranda-Foix
Research Institute ITACA, Polytechnic University of Valencia, Valencia, Spain
- 15:40-16:30 **Electromagnetic Properties of Materials: Agilent Solutions for Characterization at Microwave Frequencies and Beyond**
S.B. Begley
Agilent Technologies, Inc., Santa Rosa, CA, USA
- 16:40-17:30 **Measurements of Electromagnetic Properties of Materials at Microwave Frequencies**
J. Krupka and M. Soltysiak²
¹Institute of Radioelectronics and Optoelectronics, Warsaw University of Technology, Warsaw, Poland
²QWED sp. z o.o., Warsaw, Poland
- 17:30-18:45 **Reception – Presentations by the Seminar Sponsors:** EMPA, Room 503
- 20:00- **Seminar Gala Dinner:** Waisenhaus Ristorante, Bälliz 61, Thun
-

Tuesday, March 8, 2011

- 8:00-8:30 **On-site registration:** EMPA, Room 503

- 8:30-8:50 **Microwave Dielectric Spectroscopy in Fluids in the Supercritical and Near Critical Regions**
G.A. Dimitrakis¹, T. Fang¹, E.H. Lester¹, S.W. Kingman¹, A.P. Gregory², K. Lees², and R.N. Clarke²
¹NCIMP, University of Nottingham, Nottingham, U.K.
²Industry and Innovation Division, National Physical Laboratory, Teddington, U.K.

- 8:50-9:10 **Dielectric Measurements using Transmission Line Method and Different Sample Geometries in a WR340 Standard Waveguide**
D. Prastiyanto^{1,3}, G. Link¹, and M. Thumm^{1,2}
¹Institute for Pulsed Power and Microwave Technology, Karlsruhe Institute of Technology, Karlsruhe, Germany
²Institute of High Frequency Techniques and Electronics, Karlsruhe Institute of Technology, Karlsruhe, Germany
³Electrical and Engineering Department, State University of Semarang, Indonesia
- 9:10-9:30 **Robust, Compact, Reliable and Portable Dielectric Properties Measurement System for Powder Materials at Microwave Frequencies**
J.M. Catalá-Civera, F.L. Peñaranda-Foix, J.D. Gutierrez, P.J. Plaza-González, and A.J. Canós-Marín
Research Institute ITACA, Universidad Politécnica de Valencia, Valencia, Spain
- 9:30-9:50 **Experimental X-ray Micro Tomography: a Tool for the Development of Multi-Physics Microwave Modeling**
S. Vaucher, K. Ishizaki, M. Stir, and R. Nicula
Laboratory for Advanced Material Processing, EMPA, Thun, Switzerland
- 9:50-10:10 **Coffee break**

Session 2: Models of Material Parameters Chair: D. Bouvard

- 10:10-10:30 **Electromagnetic Modeling of Inhomogeneous Composites with Conductive Inclusions**
B. Salski¹ and M. Celuch²
¹QWED sp. z o.o., Warsaw, Poland
²Institute of Radioelectronics, Warsaw University of Technology, Warsaw, Poland
- 10:30-10:50 **Contemporary Models of Effective Permittivity and Permeability of Metal Powders – a Comparative Review**
E.M. Kiley and V.V. Yakovlev
Department of Mathematical Sciences, Worcester Polytechnic Institute, Worcester, MA, USA
- 10:50-11:10 **Modeling-Based Reconstruction of 3D Permittivity Profiles Using a Neural Network Inversion**
A.V. Brovko¹, E.K. Murphy², and V.V. Yakovlev³
¹Department of Applied Information Technologies, Saratov State Technical University, Saratov, Russia
²Applied Mathematics, Inc., Gales Ferry, CT, USA
³Department of Mathematical Sciences, Worcester Polytechnic Institute, Worcester, MA, USA

11:15-12:15 **Tour over microwave facilities of the EMPA's Laboratory for Advanced Material Processing**

12:15-13:15 **Lunch:** EMPA, Room 503

Session 3: Material Parameters in Modeling
Chair: J. Catalá-Civera

13:30-13:50 **Influence of Dielectric Properties on the Accuracy of the Simulation of Microwave Heating**

M. Soltysiak¹ and M. Celuch²

¹QWED sp. z o.o., Warsaw, Poland

²Institute of Radioelectronics, Warsaw University of Technology, Warsaw, Poland

13:50-14:10 **Simulation of Microwave Heating of Electronically Conductive Materials: Effect of Microstructure**

H.S. Park, A. Rosin, and M. Willert-Porada

Chair of Materials Processing, University of Bayreuth, Bayreuth, Germany

14:10-14:30 **Computational Study of High Temperature Microwave Processing of Zirconia: Effects of Frequency and Temperature-Dependent Material Parameters**

S. Allen¹, M. Fall¹, H. Shulman¹, and V.V. Yakovlev²

¹Ceralink, Inc., Troy, NY, USA

²Department of Mathematical Sciences, Worcester Polytechnic Institute, Worcester, MA, USA

14:30-14:50 **Coffee break**

Session 4: Microwave Processing of Materials
Chair: S. Vaucher

14:50-15:10 **Microwave Sintering of Ceramic and Metal Powders in a Single-Mode Resonant Cavity**

A. Guyon, S. Charmont, D. Bouvard, C.P. Carry, and J.-M. Chaix

Grenoble INP, Saint Martin d'Heres, France

15:10-15:30 **Microwave Processing of Electrophoretically Deposited Nanopowders**

R. Rosa¹, P. Veronesi¹, M. Michelazzi¹, C. Leonelli¹, M. Romagnoli¹, and A.R. Boccaccini²

¹University of Modena and Reggio Emilia, Italy

²University of Erlangen-Nuremberg, Germany

15:30-15:50 **Analysis of Optimum Conditions for Microwave Re-Heating of Silicate Glasses**

A. Rosin, T. Gerdes, and M. Willert-Porada

Chair of Materials Processing, University of Bayreuth, Bayreuth, Germany

15:50-16:10 **Coffee break**

Panel Session

Panelists: *S. Vaucher, M. Willert-Porada, and V.V. Yakovlev*

16:10-17:00 **Role of Material Parameters in Multiphysics Modeling**

17:00-17:15 **Closing remarks. Photo session. Seminar Closing**